

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination OH ET AL.	
		10/750,318	Examiner	Art Unit Christian Wilson
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,693,014 B2	02-2004	Fischer et al.	438/303
	B	US-			
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	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	V	Mayer et al., <i>Electronic Materials Science: For Integrated Circuits in Si and GaAs</i> , Macmillan (1990), pg. 227-232.
	W	Wolf, <i>Silicon Processing for the VLSI Era: Process Technology</i> , Lattice Press (1986), pg. 323-325.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.